

Search Notes

Application/Control No.

10/786,164

Examiner

Alvin C. Chin-Shue

Applicant(s)/Patent under
Reexamination

BEAN ET AL.

Art Unit

3634

SEARCHED

Class	Subclass	Date	Examiner
	<i>update</i>	<i>9.25.06</i>	<i>Re</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR